

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 249568US6		SERIAL NO. 10/790,006	
<div style="display: flex; align-items: center; justify-content: center;"> <div style="border: 1px solid black; border-radius: 50%; padding: 10px; text-align: center; margin: 0 10px;"> O I P E MAY 3 1 2006 PATENT & TRADEMARK OFFICE </div> <div> LIST OF REFERENCES CITED BY APPLICANT </div> </div>				APPLICANT Daisuke IMIYA, et al.			
				FILING DATE March 2, 2004		GROUP 26642616	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AM	AA	2002/0053053 A1	5/2/2002	Takeshi NAGAI, et al.			
↓	AB	6,701,372 B2	3/2/2004	Koichi Yano, et al.			
	AC	6,643,496 B1	11/4/2003	Tomohiko SHIMOYAMA, et al.			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
AM	AO	2002-204278	7/19/2002	Japan (corresponds to US 2002/0053053 A1)			
↓	AP	11-308271	11/5/1999	Japan (corresponds to US 6,701,372 B2)			
	AQ	11-341064	12/10/1999	Japan (corresponds to US 6,643,496 B1)			
	AR	2000-115245	4/21/2000	Japan (English Abstract and Unedited Computer-Generated English Translation Only)	X		
↓	AS	2002-199008	7/12/2002	Japan (corresponds to U.S. Serial Number 09/714,348)			
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner ADN GATLL					Date Considered 6/20/07		
<small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							